NSG 3060A
THE MODULAR SOLUTION FOR 6 kV APPLICATIONS

- One box solution system
- Surge voltage up to 6.6 kV allows overtesting
- Easy to use 7" color touch screen
- IEC and ANSI coupling methods
- Parameters can be changed while test is running
- Wide range of optional test accesories
- High accuracy switching technology meets ANSI coupling requirements

Teseq's new NSG 3060A conducted immunity generator takes the proven, user-friendly design of the highly successful NSG 3000 series to a new level. This innovative design uses modular architecture to provide a versatile system that can be configured for basic testing needs and expanded to meet the needs of sophisticated test laboratories.

Designed to fulfill requirements for CE mark and ANSI C62.41 testing, the NSG 3060A performs tests for Combination wave surge, Ring wave and Electrical Fast Transient (EFT) pulses as well as Power Quality Testing (PQT). Extensive expansion capabilities enable the system to be configured for a much broader range of applications.

Using state of the art components, the self-contained modules set new standards with respect to switching and phase accuracy and exceed the existing standards' requirements. With its powerful processors, the NSG 3060A can completely fulfill the unique coupling requirements specified by ANSI C62.41. This standard requires that the pulse amplitude be adjusted for the phase position of the pulse on the AC mains, and for the amplitude of the mains voltage.

A 7" touch panel display with superb contrast and color is the most striking feature of the new NSG 3060A. For fast and efficient data entry, input devices include an integrated keyboard and a thumbwheel with additional keys for sensitivity adjustment.

The user-friendly graphic display speeds test setup. Each parameter's value is highly visible, and all settings can be quickly selected and modified with the generously sized touch input buttons. A stylus is not necessary, and ramp functions are programmed quickly and easily. Multi-step test procedures can be created and their sequence or parameter values changed easily.

The users can make manual parameter changes using the thumbwheel while a test is under way, providing an effective and fast method for identifying critical threshold values. The Test Assistance (TA) function allows users to initiate standardized test with just a few "clicks" to achieve quick, reliable results in a development environment.

The NSG 3060A has an Ethernet port for external PC control. The Windows-based control software simplifyes test programming and allows compilation of complex test sequences with diverse pulse types. Test reports can be generated during the test operation, allowing the operator to enter observations as the test progresses and increasing the efficiency of long-term tests.

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Model	EFT/Burst	Surge	PQT	Ring wave	Telecom-Surge
NSG 3060A-IEC	■	■	■		
NSG 3060A-ANSI	■	■	■	■	
NSG 3060A-FULL	■	■	■	■	■

The NSG 3060A performs tests according to the following specifications:

Combination wave pulse 1, 2/50 - 8/20 µs (Hybrid-Surge pulse)

Pulse conforms to IEC/EN 61000-4-5 and ANSI (IEEE) 62.41

Parameter	Value
Pulse voltage (open circuit):	±200 V to 6.6 kV (in 1 V steps)
Pulse current (short circuit):	±100 A to 3.3 kA
Impedance:	2/12 Ω
Polarity:	positive / negative / alternate
Pulse repetition:	10 s* up to 9'999 s (in 1 s steps)
Test duration:	1 to 99'999 pulses, continuous
Phase synchronization:	asynchronous, synchronous 0 to 359° (in 1° steps)
Coupling:	ANSI / IEC / external

* Repetition rate depends on voltage:
200 to 4400 V = 10 s repetition time
4401 to 6600 V = 20 s repetition time

Ring wave 0.5 µs/100 kHz

Pulse conforms to IEC/EN 61000-4-12 and ANSI (IEEE) C62.41

Parameter	Value
Pulse voltage (open circuit):	± 200 V to 6.6 kV (in 1 V steps)
Pulse current (short circuit):	±16.6 to ±550 A, ±10% ±6.6 to ±220 A, ±10% ±1 to ±33 A, ±10%
Impedance:	12/30 Ω
Polarity:	positive / negative / alternate
Pulse repetition:	10 s* up to 9'999 s (in 1 s steps)
Test duration:	1 to 99'999 pulses, continuous
Phase synchronization:	asynchronous, synchronous 0 to 359° (in 1° steps)
Coupling:	ANSI / IEC / external

* Repetition rate depends on voltage:
200 to 4400 V = 10 s repetition time 4401
to 6600 V = 20 s repetition time

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Burst (EFT) 5/50 ns

Pulse conforms to IEC/EN 61000-4-4

Parameter	Value
Pulse amplitude:	±200 V to 4.8 kV (in 1 V steps) - open circuit ±100 V to 2.4 kV (50 Ω matching system)
Burst frequency:	100 Hz to 1000 kHz
Polarity:	positive / negative / alternate
Repetition time:	10 ms to 9'999 ms
Burst time:	0.01 ms to 9'999 ms, single pulse
Test duration:	1 s to 9'999s, 1 min to 1600 min, endless
Phase synchonization:	asynchronous, synchronous 0 to 359° (in 1° steps)
Coupling:	internal / external

Dips & Interrupts

conforms to IEC / EN 61000-4-11, IEC / EN 61000-4-29

Parameter	Value
Dips & Interrupts:	From EUT voltage input to 0 V, 0% (1)
Uvar with optional variac:	depending on model (VAR 3005A)
Uvar with step transformer:	0, 40, 70, 80% (INA 650xA)
Peak inrush current capability:	> 500 A (at 230 V)
Switching times:	1 to 5 µs (100 Ω load)
Event time (T-Event):	20 µs to 9999 s, 0.5 to 9'999 cycles
Repetition time:	10 ms to 9'999 ms, 1 to 9'999 s
Test duration:	1 to 99'999 events, endless
Phase synchronization:	asynchronous, synchronous 0 to 359° (in 1° steps)

(1) In combination with VAR 3005A-S16, effective minimal dip voltage ~8 V. As specified in IEC 61000-4-11, chapter. 5.1 a test voltage level from 0% to 20% of the rated voltage is considered as a total interruption.

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Variation test (with VAR 3005A-S16 only)

Parameter	Value
Uvar with optional variac:	up to 265 V (in 1 V steps) or up to 115% Uin (in 1% steps)
Decreasing time Td:	1 ms to 9.999 ms, 0.5 to 9999 cycles, abrupt
Time at reduced voltage Ts:	1 ms to 9.999 ms, 0.5 to 9999 cycles,
Increasing time Ti:	1 ms to 9.999 ms, 0.5 to 9999 cycles,
Repetition time:	1 s to 9'999 s
Events:	1 to 99'999

Pulsed magnetic field in conjunction with MFC 30
conforms to IEC/EN 61000-4-9

Parameter	Value
Field:	100 to 1200 A/m
Polarity:	positive / negative / alternate
Repetition time:	10 s to 9999s (in 1 s steps)
Impedance:	2 Ω
Coil / impedance factor:	0.01 to 100.00
Test duration:	1 to 9'999 pulses, endless
Phase synchronization:	asynchronous, synchronous 0 to 359° (in 1° steps)

Power magnetic field in conjunction with MFT 30 or MFO 6501A and MFC 30 / MFC 300
conform to IEC/EN 61000-4-8

Parameter	Value
Field:	1 to max. 40 A/m (in 1 A/m steps)
Frequency:	50/60 Hz
Coil factor:	0.01 to 99.99
Test duration:	1 to 9'999 pulses, continuous

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Internal coupling network

Parameter		Value
EUT supply:		1-phase
EUT VAC:		Up to 300 Vrms *, 50 / 60 Hz (phase - neutral)
EUT VDC:		Up to 300 VDC
EUT current		1 x 16 Arms continuous (over heat protected)
Connections:	Front panel:	- EUT: 4mm banana plug - Burst OUT 50 Ω SHV - Trigger out BNC
	Rear panel	- EUT supply: banana plug 4 mm - Additional ground connector - Instrument supply 85 V to 264 VAC - Connector surge HV – COM
Surge		Standard coupling as per IEC 61000-4-5
Coupling mode		Line to Line Line(s) to ground
Mains decoupling:		1.5 mH 0% + 35%
Decoupling attenuation:		Residual pulse voltage on EUT power supply inputs 15 % max. Residual voltage on non-pulsed EUT power supply inputs 15 % max.
EFT (Burst)		Standard coupling all lines to ref ground (GND) IEC / EN 61000-4-4 L, N, PE to ref GND
		Any lines and combinatio to ref GND: L to ref GND N to ref GND PE to ref GND L, N to ref GND L, PE to ref GND N, PE to ref GND
PQT:		Dips & interrupts to phase L

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Technical specification	
Instrument supply	85 to 265 VAC, 50 / 60 Hz
Dimensions NSG 3060A-IEC	19”; 6 HU, 448 x 289 x 500 mm (W x H x D)
Weight NSG 3060A	30 kg (66 lbs)

Options	
CDN 3063A-C32	Three phase 480 V / 32 A automatic coupling decoupling networks for Burst/EFT up to 4.8 kV, Surge, Ring Wave pulses up to 6,6 kV
CDN 3063A-C63	Three phase 480 V / 63 A automatic coupling decoupling network for Burst/EFT up to 4.8 kV, Surge, Ring Wave pulses up to 6,6 kV
CDN 3063A-C100	Three phase 480 V / 100 A automatic coupling decoupling network for Burst/EFT up to 4.8 kV, Surge, Ring Wave pulses up to 6,6 kV
CDN 3425	Burst EFT capacitive coupling clamp for data line coupling per IEC 61000-4-4
CDN 117A-C6-4-1	Coupling networks for unsymmetrical signal-/data lines (surge)
CDN 118A-C6-4-1	Coupling networks for symmetrical signal-/data lines (surge)
CDN HSS-2	Coupling network for 2 kV surge pulse 1.2 / 50 µs IEC/EN 61000-4-5 on unshielded symmetrical high speed telecom lines (Ethernet)
PVF BKIT 1	Burst/EFT verification set
MD 210	Voltage differential probe 7 kV common / differential 1000:1 / 100:1
MD 300	Current probe 5 kA
Accessories for IEC/EN 61000-4-11	
TVT 1-250-16	Manual step transformer, 16 AAC, 0/40/70/80%
VAR 3005A-S16	Automatic single variable transformer, 1 x 16 A
Accessories for IEC/EN 61000-4-8/-4-9	
MFO 6501A	Manual magnetic field option -4-8
MFC 30	Magnetic field coil 1 x 1 m, with MFO max. 40 A/m -4-8; Surge* max. 1200 A/m -4-9
MFC 300	Magnetic field coil 1 x 1 m; max. 330 A/m -4-8

AMETEK CTS GmbH
Sternenhofstrasse 15 4153 Reinach Switzerland

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COMPLIANCE TEST SOLUTIONS

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